

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination SATO ET AL	
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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,831,129	12-2004	Sato et al.	525/58
*	B US-6,558,797	05-2003	Arata et al.	428/418
*	C US-2002/0106516	08-2002	Sato et al.	428/413
*	D US-5,874,009	02-1999	Inada et al.	216/20
*	E US-5,965,269	10-1999	Inada et al.	428/413
*	F US-6,730,402	05-2004	Kuchi et al.	428/414
*	G US-6,162,878	12-2000	Osada et al.	525/481
*	H US-5,916,683	06-1999	Ueda et al.	428/418
*	I US-6,165,617	12-2000	Satoh et al.	428/418
*	J US-5,674,611	10-1997	Saida et al.	428/344
*	K US-5,800,722	09-1998	Tsuyoshi et al.	216/13
*	L US-6,652,962	11-2003	Sato et al.	428/352
*	M US-6,716,530	04-2004	Sato et al.	428/416

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	EP 1 116 774	07-2001	EP	Tobisawa	
O	EP 1 092 739	04-2001	EP	Nakamura et al	
P	JP 2000-265039	09-2000	JP	Suzuki	
Q	JP 2003-198141	07-2003	JP	Fujita et al	
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

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Notice of References Cited		Application/Control No. 10/523,698	Applicant(s)/Patent Under Reexamination SATO ET AL	
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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2004/0149658	08-2004	Dukhin et al.	210/638
*	B US-2004/0101696	05-2004	Yamazaki et al.	428/457
*	C US-6,905,757	06-2005	Matsushima et al.	428/209
*	D US-5,298,548	03-1994	Shiobara et al.	523/443
*	E US-4,477,512	10-1984	Thomas et al.	442/180
*	F US-6,620,513	09-2003	Yuyama et al.	428/416
*	G US-6,426,146	07-2002	Ameen et al.	428/413
*	H US-6,187,416	02-2001	Sato et al.	428/209
*	I US-2003/0069331	04-2003	Teiichi et al.	523/176
*	J US-5,308,895	05-1994	Gan et al.	523/445
*	K US-6,723,801	04-2004	Akatsuka et al.	525/491
*	L US-2007/0243402	10-2007	Sato et al.	428/606
*	M US-2007/0102804	05-2007	Nakamura et al.	257/698

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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